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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/662,682 09/15/2000		Xiuling Li	1201.64722	1914	
7:	590 07/08/2003		•		
Steven P. Fallon GREER, BURNS & CRAIN, LTD. 300 S. WACKER DRIVE			EXAMINER		
			VINH, LAN		
SUITE 25	DIC DIC V D				
Chicago, IL 6	0606-6752		ART UNIT	PAPER NOMBER	
			1765	17	
			DATE MAILED: 07/08/2003		

Please find below and/or attached an Office communication concerning this application or proceeding.

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			Application No.	Applicant(s)	
•			09/662,682	LI ET AL.	
		Office Action Summary	Examin r	Art Unit	<u> </u>
		•	Lan Vinh	1765	
De		The MAILING DATE of this communication ap or Reply	pears on the cover sheet with th	ne correspondence addre	ss
_			VIC SET TO EVRIRE 2 MONT	FU(S) EDOM	•
	THE - External after - If the - If NO - Failure - Any	ORTENED STATUTORY PERIOD FOR REPLICATION. MAILING DATE OF THIS COMMUNICATION. Insions of time may be available under the provisions of 37 CFR 1. SIX (6) MONTHS from the mailing date of this communication. It period for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period reply within the set or extended period for reply will, by statutely reply received by the Office later than three months after the mailing patent term adjustment. See 37 CFR 1.704(b).	.136(a). In no event, however, may a reply body within the statutory minimum of thirty (30) will apply and will expire SIX (6) MONTHS te, cause the application to become ABAND	ne timely filed days will be considered timely. from the mailing date of this comm DNED (35 U.S.C. § 133).	unication.
St	tatus				
	1)⊠	Responsive to communication(s) filed on 28			
	2a) <u></u> □	This action is FINAL . 2b)⊠ T	his action is non-final.		•
	3)	Since this application is in condition for allow closed in accordance with the practice unde			nerits is
Di	sposit	ion of Claims	Lx parte Quayle, 1955 O.D. 1	1, 400 0.0. 210.	
	4)⊠	Claim(s) 1-21 is/are pending in the application	on.		
		4a) Of the above claim(s) is/are withdra	awn from consideration.		
	5) 🗌	Claim(s) is/are allowed.	•		
	6)⊠	Claim(s) <u>1-21</u> is/are rejected.			
	7)	Claim(s) is/are objected to.			
		Claim(s) are subject to restriction and/	or election requirement.	,	
Ąŗ		ion Papers	•		
		The specification is objected to by the Examin			
	10) 📙	The drawing(s) filed on is/are: a) acce			
	44)[7]	Applicant may not request that any objection to the			
	11)	The proposed drawing correction filed on		proved by the Examiner.	•
	12)□	If approved, corrected drawings are required in re The oath or declaration is objected to by the E	• •		
D.		under 35 U.S.C. §§ 119 and 120	Adminici.		
		Acknowledgment is made of a claim for foreign	an priority under 25 U.S.C. \$ 11	0(a) (d) as (f)	
	•	☐ All b)☐ Some * c)☐ None of:	gn phonty under 35 0.3.C. § 11	9(a)-(u) or (r).	
	u)ı	1.☐ Certified copies of the priority documen	ats have been received		
		2. Certified copies of the priority document		cation No	•
		3. Copies of the certified copies of the prior			ano.
	* 5	application from the International B See the attached detailed Office action for a lis	ureau (PCT Rule 17.2(a)).		ige
•	14) 🗌 <i>F</i>	Acknowledgment is made of a claim for domes	tic priority under 35 U.S.C. § 11	19(e) (to a provisional ap	plication).
) The translation of the foreign language pracknowledgment is made of a claim for domes	• •		
Att	tachmen	t(s)			
2)	☐ Notic	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449) Paper No(s) <u>:</u>	5) Notice of Inform	nary (PTO-413) Paper No(s). nal Patent Application (PTO-15	

Art Unit: 1765

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 1-2, 4-5, 10, 11-12, 14-15 are rejected under 35 U.S.C. 102(b) as being anticipated by Lee et al (US 5,565,084)

Lee discloses an electropolishing method for etching substrate. This method comprising/consisting of the steps of:

coating a metal/gold layer on the silicon substrate, the metal layer having a thickness of 1000 angstroms (100 nm) (col 3, lines 64-65, col 4, lines 32-33, fig. 1F shows a thin discontinuous metal layer 15 formed on the Si substrate 11), which reads on depositing a thin discontinuous layer of metal on a Si surface

immersing the gold/metal coated Si substrate in a HF and nitric acid solution, the HF in the etchant solution make the Si substrate porous, etching the Si substrate by breaking the supply of the electricity for 1 minutes (col 4, lines 31-43), which reads on forming the porous silicon by etching the Si surface having the discontinuous layer in a HF and oxidant solution for a period of about two second up to 60 minutes, the etching being conducted without external electrical bias

Regarding claims 2, 12, Lee is silent about the use of illumination during the etching step which reads on the step of etching is conducted in the absence of illumination.

Art Unit: 1765

Regarding claims 4, 14, Lee discloses using Pt as the metal layer (col 3, lines 64-65)

The limitations of claims 5, 10,15 have been discussed above.

3. Claim 21 is rejected under 35 U.S.C. 102(b) as being anticipated by Lee et al (US 5,565,084)

Lee discloses an electropolishing method for etching substrate. This method comprising/consisting of the steps of:

coating a metal/gold layer on the silicon substrate; the metal layer having a thickness of 1000 angstroms (100 nm)/nanosize (col 3, lines 64-65, col 4, lines 32-33, fig. 1F shows a thin discontinuous metal layer 15 formed on the Si substrate 11). Since Lee discloses forming the discontinuous metal layer of the same material (gold) and having a thickness of the same dimension (nanosize) as the claimed metal layer, it is inherent that Lee's metal layer having a thickness sufficient to permit nucleation that form nanometer size metal particles and small enough to prevent formation of a continuous metal layer

immersing the gold/metal coated Si substrate in a HF and nitric acid solution, the HF in the etchant solution make the Si substrate porous, etching the Si substrate by breaking the supply of the electricity for 1 minutes (col 4, lines 31-43), which reads on forming the porous silicon by etching the Si surface having the discontinuous layer in a HF and oxidant solution for a period of about two second up to 60 minutes, the etching being conducted without external electrical bias

Art Unit: 1765

Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claims 3, 13 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lee et al (US 5,565,084) in view of Russell et al (US 6,093,941)

Lee's method has been described above in paragraph 2. Lee differs from the instant claimed inventions as per claims 3, 13 by conducting the etching without the illumination instead of conducting the etching in the presence of illumination.

However, Russell, in a method of forming porous region in a light emitting silicon structure, teaches that luminescent porous silicon can be produced using either chemical stain etch (without illumination) or photochemical etch (with illumination) (col 6, lines 65-67; col 7, lines 10-12)

Hence, one skilled in the art would have found it obvious to modify Lee etching step to form porous silicon by conducting the etching in the presence of illumination in view of Russell teaching because Russell discloses that as the illumination time during etching increases, the etching spreads out to regions of the silicon which were not illuminated and small etched features becomes washed out consistent with the generation of holes/pores required for the catalysis of the etching mechanism (col 6, lines 9-13)

Art Unit: 1765

6. Claims 6, 7, 16-18 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lee et al (US 5,565,084) in view of Yoshikawa et al (US 5,990,605)

Lee's method has been described above in paragraph 2. Lee differs from the instant claimed invention as per claims 6, 16 by depositing a metal layer of gold (Au) instead of Pd (Palladium)

However, Yoshikawa, in a method of forming an electron emission device include a porous semiconductor, discloses that Au or Pd can be used as metal coating on a porous silicon surface 13 (col 7, lines 31-35)

Hence one skilled in the art would have found it obvious to substitute Lee metal layer of Au with Pd in view of Yoshikawa teaching because both Au and Pd are known metals for using as a metal coating on a porous surface, thus the substitution of one for the other would have produced an expected result.

Unlike the instant claimed invention as per claims 7, 17, 18, Lee does not specifically discloses forming a combination of metals selected from the group consisting of :Au, Pt and Pd.

Yoshikawa also discloses that metals of Au, Pt and Pd can be used as an alloy metal coating on a porous silicon surface 13 (col 7, lines 31-37) which reads on using a combination of metals selected from the group consisting of :Au, Pt and Pd.

Hence one skilled in the art would have found it obvious to modify Lee metal layer by forming an alloy metal layer as per Yoshikawa because Yoshikawa states that an alloy/combination of metal contain Au and Pt is desirable to make the thin film metal very thin to increase electron emission (col 7, lines 45-49)

Art Unit: 1765

7. Claims 8, 19 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lee et al (US 5,565,084) in view of Hwang et al (US 4,681,657)

Lee method has been described above in paragraph 2. Lee differs from the instant claimed inventions as per claim 8, 19 by etching using HF and an oxidant of HNO₃ instead of HF and an oxidant H₂O₂.

However, Hwang discloses that HNO_3 and H_2O_2 can be used as oxidizer/oxidant in a HF solution that is used to wet etch silicon wafer (col 1, lines 8-14)

Hence, one skilled in the art would have found it obvious to substitute Lee etching solution of HF and HNO_3 with an etching solution of HF and H_2O_2 in view of Hwang teaching because both etching solutions have the same function of wet etching silicon; therefore, the substitution of one for the other would have produced an expected result.

8. Claims 9, 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lee et al (5,565,084) in view of Yoshikawa et al (US 5,990,605)

Lee's method has been described above in paragraph 2. Although Lee discloses forming a thin metal coating of Au/Pt on the silicon surface, Lee does not specifically disclose that the thickness of the metal is less than approximately 10 nm.

However, Yoshikawa discloses a method of forming an electron emission device include a porous semiconductor comprises the step of forming a thin (thickness of 2 nm)/less than approximately 10 nm metal layer 15 on a porous silicon surface 13 (col 7, lines 51-54)

Art Unit: 1765

Since Lee discloses forming a thin metal coating of Au/Pt, one skilled in the art would have found it obvious to modify Lee metal forming step by forming a thin metal layer having the thickness as taught by Yoshikawa because according to Yoshikawa when considering the stability as an electron/light emission device a thin (2nm) is the most suitable for the Au or Pt thin film/coating on a porous surface (col 7, lines 53-55)

Response to Arguments

Applicant's arguments with respect to claims 1-21 have been considered but are 9. moot in view of the new ground(s) of rejection.

Conclusion

10. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Lan Vinh whose telephone number is 703 305-6302. The examiner can normally be reached on M-F 8:30-5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Benjamin Utech can be reached on 703 308-3836. The fax phone numbers for the organization where this application or proceeding is assigned are 703 872-9310 for regular communications and 703 872-9311 for After Final communications.

July 3, 2003